# Reliability Analysis Based on a Mathematical Tool

## Jahangir Ghajar Dowlatshahi 🗌 Unisys 🗌 Eagan

Key Words: Mathematical Toolbox, Symbolic notation, Coverage, Markov Analysis.

#### ABSTRACT

The reliability engineering analysis task involves understanding system requirements, modeling the system to respond to these requirements, applying the right mathematical equations that run the model, extracting the results, changing the parameters, and then analyzing them for the optimum design goals (sensitivity analysis, trend analysis, life cycle analysis, growth analysis, and so forth).

One of the most difficult and time-consuming aspects of a system reliability analysis cycle (especially for large, complex, and fault tolerant systems) is the mathematical computations of the system reliability. Personal computers with spreadsheet programs have been successfully used to perform reliability analysis. The mathematical formulas for these applications are usually entered into a macro and exist in the cells of the spreadsheet, or stay in a library of specialized functions to be called to the spreadsheet when required. A new generation of mathematical tools (Mathematical Toolboxes) featuring symbolic notation, a rich source of mathematical functions, graphics and text capabilities, are currently on the market. These tools take the burden of complex and tedious mathematical computations from the reliability engineer and leave the engineer with the basics of reliability engineering design.

This paper describes one such tool that has been used to model systems with redundancy and coverage. Coverage is the probability of automatically recovering from faults within a specified time and without affecting normal system operation.

#### INTRODUCTION

Those of us in the reliability engineering world have experienced the great value of statistical problem solver software programs and have also experienced situations in which no existing software programs could solve our problems completely.

System reliability analysis (especially for fault tolerant systems) adds another dimension to the difficulty and complexity of analysis techniques. This is because various reliability analysis techniques and procedures must be integrated into one system. In many instances, the reliability engineer puts different procedures and solution strategies together in order to solve a special application, by trying to answer the following questions step-by-step:

1. Are the system modules in series/parallel?

Г

2. Is the system repairable or non-repairable?

3. Are failures in the system mutually independent?

4. Has the system full coverage or is coverage < 1?

5. Is the system time-dependent or failure-dependent?6. Can the assumption of exponential distribution for failures hold, or should the engineer use a different distribution?

A mathematical reliability model can then be generated to represent the actual operational system. Without a powerful simulation and computation tool, the analysis of the model proves to be very cumbersome in many specialized systems.

Added to these problems is the computation/analysis of software reliability, with numerous approaches to solve them. There is virtually no single statistical/mathematical software package that can resolve every reliability problem that engineers would face.

Mathematical Toolboxes, with symbolic manipulation capability to perform algebraic calculations, are currently used heavily in the scientific and engineering arenas. The mathematical operation is usually performed sequentially starting with the definitions of constants and variables, followed by the application formulas. Text can be inserted at any point to define the assumptions, mathematical approaches, procedures and analysis techniques, etc. Numerical results can be obtained at every step of computation.

Mathematical Toolboxes in the hands of the reliability engineers are valuable tools to perform step-by-step sequential and logical reliability analysis. All steps are clearcut, readable, and easily understood as the analysis proceeds. There are no hidden formulas/equations, functions, or rules defining the process. Each step can be evaluated (e.g., using sensitivity analysis and plotting the results), validated, and integrated into the system model. The results can then be tested and evaluated for the overall system reliability performance. The final result is an excellent documentation of the processes involved in modeling and analyzing a system reliability problem.

A powerful environment, in which one can build a prototype/simulation of an actual reliability application, allowing rapid change and refinement, is easy to achieve. Standard numerical methods such as integration, solution of differential equations, and matrix/vector operations, so widely used in the Markov reliability modeling, can be very efficiently implemented using Mathematical Toolboxes.

The following examples have been specially selected to demonstrate the capability of one such Mathematical Toolbox, the MathCAD tool, as used by the author to solve and document the reliability problems. The examples presented in this paper assume independence among the subsystems comprising the total system, except for the Markov models where dependencies among lower system units exist.

0149 144X/90/0000-0465\$01.00 © 1990 IEEE

## 1990 PROCEEDINGS Annual RELIABILITY AND MAINTAINABILITY Symposium

465

## **EXAMPLE 1 - NO-REPAIR SERIAL SYSTEM**



Define Constants and Variables:

ī

T := 0..100**Mission Duration** 

Mean Time to Failure (MTTF) for Units A, B, C, and D:

MTTFA := 1000	MTTFB := 2000
MTTFC := 500	MTTFD := 200

**Reliability For Each Block:** 

$R_A(T) := e^{-\left[\frac{T}{MTTFA}\right]}$	First block
$R_B(T) := e^{-\left[\frac{T}{MTTFB}\right]}$	Second block
$R_C(T) := e^{-\left[\frac{T}{MTTFC}\right]}$	Third block
$R_D(T) := e^{-\left[\frac{T}{MTTFD}\right]}$	Fourth block

System Reliability:

 $\label{eq:response} R\_system(T) := R\_A(T) \cdot R\_B(T) \cdot R\_C(T) \cdot R\_D(T)$  $R_{system}(100) = 0.427415$ 

System Mean Up Time (MUT):

$$MUT := \frac{\int_{0}^{100} R_A(T) \cdot R_B(T) \cdot R_C(T) \cdot R_D(T) dT}{1 - R_{system}(100)}$$
$$MUT = 117.65$$

#### **EXAMPLE 2 - NO REPAIR PARALLEL/** SERIAL SYSTEM



Define Constants and Variables:

T

Operation time (variable, in steps of 50 up to 1000 hours)

MTTF1 := 1000 MTTF for Block A MTTF2 := 200 MTTF for Block B MTTF3 := 500 MTTF for Block C MTTF4 := 5000 MTTF for Block D

Т

1990 PROCEEDINGS Annual RELIABILITY AND MAINTAINABILITY Symposium

Reliability for first stage:

$$R_A(T) := e^{-\left[\frac{T}{MTTF1}\right]} \qquad Block A \qquad -\left[\frac{A}{A}\right]^{-1}$$

$$R_STAGE1(T) := R_A(T) \qquad Stage 1$$

Reliability for second stage :

$$\mathbf{R}_{\mathbf{B}}(\mathbf{T}) := e^{-\left[\frac{\mathbf{T}}{\mathbf{M}\mathbf{T}\mathbf{T}\mathbf{F}^{2}}\right]}$$

$$R\_STAGE2(T) := R\_B(T)^2 + 2 \cdot R\_B(T) \cdot (1 - R\_B(T))$$
  
Stage 2 (1 of 2  
required)

Block B

Reliability for third stage:

$$R_{C}(T) := e^{-\left[\frac{T}{MTTF3}\right]} \qquad Block C \qquad \begin{bmatrix} \overline{C} & \overline{J} \\ -\overline{J} & \overline{J} \\ -\overline{$$

$$R_STAGE3(T) := R_C(T)^3 + 3 \cdot R_C(T)^2 \cdot (1 - R_C(T))$$
  
Stage 3 (2 of 3  
required

Reliability for the fourth stage:

Block D  $R D(T) := e^{-\left[\frac{T}{MTTF4}\right]}$  $R_STAGE4(T) := R_D(T)$ Stage 4

System Reliability Analysis:

$$R_system(T) := R_STAGE1(T) \cdot R_STAGE2(T) \cdot R_STAGE3(T) \cdot R_STAGE4(T)$$

urs mission

System reliability as a function of operation time can be plotted as shown here:



System Mean Up Time (MUT):

$$MUT := \frac{\int_{0}^{1000} R_system(T) dT}{1 - R_system(1000)}$$

MUT = 179.286

## EXAMPLE 3 – REPAIRABLE, LOWER LEVELS IN PARALLEL, COVERAGE = 1

- I

Stage 1 Stage 2 Stage 3

Define Constants and Variables:

1

MTTF_A := 1000	$MTTR_A := 1$
$MTTF_B := 500$	$MTTR_B := 1$
$\mathbf{MTTF}\mathbf{C} := 200$	$\mathbf{MTTR} \mathbf{C} := 2$
$\mathbf{MTTF}\mathbf{D} := 1000$	$MTTR_D := 5$
$\mathbf{MTTF}\mathbf{E} := 300$	$\mathbf{MTTR}\mathbf{E} := 10$

Reliability for the first stage:

$MTTF_S1 := MTTF_A$	Stage 1 MTTF
MTTR_S1 := MTTR_A	Stage 1 MTTR

## Reliability for the second stage:

\_\_\_\_\_\_

Т

Using the Einhorn model, the MTTFs of the combined "B" branches are:

$MTTF_B1 := \frac{MTTF_B^2}{2 \cdot MTTR_B}$	MTTF for 1 of 2 parallel B units
MTTF $B1 = 125000$	
N := 2	Number of B units in parallel
R := 1	Number of B units required
$\mathbf{MTTR}_{\mathbf{B}1} := \frac{\mathbf{MTTR}_{\mathbf{B}}}{\mathbf{N} - \mathbf{R} + 1}$	MTTR of parallel units using Ein-
$MTTR_B1 = 0.5$	norm equation
$MTTF_C1 := \frac{MTTF_C^3}{3 \cdot MTTR_C^2}$	MTTF for 1 of 3 parallel C units
$MTTF_C1 = 666667$	
N := 3	Number of C units in parallel
R := 1	Number of C units required
$MTTR_C1 := \frac{MTTR_C}{N - R + 1}$	MTTR of parallel units using the Ein-
$MTTR\_C1 = 0.667$	nom definition

Stage 2 MTTF and MTTR for the parallel non-identical units are:

MTTR\_S2 := 
$$\frac{1}{\frac{1}{MTTR_B1} + \frac{1}{MTTR_C1}}$$
Stage 2 MTTRMTTR\_S2 = 0.286U\_B1 :=  $\frac{MTTR_B1}{MTTF_B1 + MTTR_B1}$ Unavailability  
of B1 unitU\_B1 = 4 \cdot 10^{-6}U\_C1 :=  $\frac{MTTR_C1}{MTTF_C1 + MTTR_C1}$ Unavailability  
of C1 unitU\_C1 = 1 \cdot 10^{-6}Stage 2 Unavailability  
of C1 unitStage 2 Unavailability  
of C1 unitU\_S2 := U\_B1 \cdot U\_C1Stage 2 Unavailability  
u\_S2 := MTTR\_S2 \cdot  $\frac{1 - U_S2}{U_S2}$ Stage 2 MTTFMTTF\_S2 = 7 \cdot 143 \cdot 10^{10}Stage 2 MTTF

Reliability for the third stage:

 $MTTF_E1 := \frac{MTTF_E^2}{2 \cdot MTTR_E}$  $MTTF_E1 = 4500$ 

N := 2	Number of E units in parallel
$\mathbf{R} := 1$	Number of E units required

$$MTTR_E1 := \frac{MTTR_E}{N - R + 1}$$
$$MTTR_E1 = 5$$

Stage 3 MTTF and MTTR for the parallel non-identica units are:

$MTTR\_S3 := \frac{1}{\frac{1}{MTTR\_D} + \frac{1}{MTTR\_E1}}$	Stage 3 MTTR
$MTTR_S3 = 2.5$	×.
$U_D := \frac{MTTR_D}{MTTF_D + MTTR_D}$	Unavailability of D unit
$U_D = 0.005$	
$U_{E1} := \frac{MTTR_{E1}}{MTTR_{E1} + MTTF_{E1}}$	Unavailability of combined E units
$U_E1 = 0.001$	
$U_{S3} := U_D \cdot U_E1$	Stage 3 Unavail- ability
$MTTF_S3 := MTTR_S3 \cdot \frac{1 - U_S3}{U_S3}$	Stage 3 MTTF
$MTTF_S3 = 4.528 \cdot 10^5$	

1990 PROCEEDINGS Annual RELIABILITY AND MAINTAINABILITY Symposium

467

ï

System Analysis

ī

System Mean Up Time (MUT)

$$MUT := \frac{1}{\frac{1}{MTTF_{S1}} + \frac{1}{MTTF_{S2}} + \frac{1}{MTTF_{S3}}}$$

MUT = 998

System Mean Down Time (MDT)

$$MDT := \frac{\frac{1}{MTTF_{S1}} \cdot MTTR_{S1} + \frac{1}{MTTF_{S2}} \cdot MTTR_{S2} + \frac{1}{MTTF_{S3}} \cdot MTTR_{S3}}{\frac{1}{MUT}}$$
$$MDT = 1.0033$$

System Availability (AVAIL) :

$$AVAIL := \frac{MUT}{MUT + MDT}$$
$$AVAIL = 0.999$$

#### **EXAMPLE 4 - STEADY STATE MARKOV, COVERAGE** < 1



In this example, the effect of redundancy and stand-by operation is examined.

Assumptions:

#### One of two units, degraded mode

The coefficients of the matrix are:

$$\begin{aligned} a &:= 2 \cdot \lambda \cdot COV & c &:= 2 \cdot \lambda \cdot (1 - COV) \\ b &:= \frac{1}{MTTR} & d &:= \lambda \end{aligned}$$

The matrix equations are:

$$M := \begin{bmatrix} -(a + c) & b \\ a & -(b + d) \end{bmatrix} \quad V := \begin{bmatrix} -1 \\ 0 \end{bmatrix}$$
$$\begin{bmatrix} T1 \\ T2 \end{bmatrix} := M^{-1} \cdot V \qquad \begin{array}{c} T1 \text{ and } T2 \text{ are the times} \\ \text{spent in states 1 and 2,} \\ \text{respectively.} \end{array}$$

 $\mathbf{MTTF} := \mathbf{T1} + \mathbf{T2}$ 

MTTF can be found by summing the times spent in the two Up states

MTTF = 4964

One of two units, hot stand-by (one unit is active):

$$\begin{split} \mathbf{a} &:= \lambda \cdot \mathrm{COV} + \lambda \\ \mathbf{c} &:= \lambda \cdot (1 - \mathrm{COV}) \\ \mathbf{M} &:= \begin{bmatrix} -(\mathbf{a} + \mathbf{c}) & \mathbf{b} \\ \mathbf{a} & -(\mathbf{b} + \mathbf{d}) \end{bmatrix} \quad \mathbf{V} \quad := \begin{bmatrix} -1 \\ 0 \end{bmatrix} \\ \begin{bmatrix} T1 \\ T2 \end{bmatrix} &:= \mathbf{M}^{-1} \cdot \mathbf{V} \\ \mathbf{MTTF} &:= \mathbf{T1} + \mathbf{T2} \\ \mathbf{MTTF} &:= \mathbf{T1} + \mathbf{T2} \\ \mathbf{MTTF} &:= \mathbf{P832} \end{split}$$

Cold standby (one unit is active, the other is non-operating):

$$\begin{split} \mathbf{a} &:= \lambda \cdot \text{COV} \\ \mathbf{c} &:= \lambda \cdot (1 - \text{COV}) \\ \mathbf{M} &:= \begin{bmatrix} -(\mathbf{a} + \mathbf{c}) & \mathbf{b} \\ \mathbf{a} & -(\mathbf{b} + \mathbf{d}) \end{bmatrix} \\ \begin{bmatrix} T1 \\ T2 \end{bmatrix} &:= \mathbf{M}^{-1} \cdot \mathbf{V} \\ \mathbf{MTTF} &:= T1 + T2 \\ \mathbf{MTTF} &= 9920 \end{split}$$

$$:= \begin{bmatrix} -1\\ 0 \end{bmatrix}$$

v

T1 and T2 are the times spent in states 1 and 2, respectively.

EXAMPLE 5 - NON-IDENTICAL, REPAIRABLE, COVERAGE < 1 MTTF MODEL, MARKOV ANALYSIS



Define Constants and Variables:

$MTTF_A := 1000$	MTTF for unit A
$\mathbf{MTTF}\mathbf{B} := 500$	MTTF for unit B
MTTRA := 1	MTTR for unit A
MTTRB := 1	MTTR for unit B
$COV \ \overline{A:} = .95$	Coverage for unit A
COV_B:= .99	Coverage for unit B

468

1990 PROCEEDINGS Annual RELIABILITY AND MAINTAINABILITY Symposium

T

The coefficients of the matrix are:

i.

all := 
$$\frac{1}{\text{MTTF}_A} + \frac{1}{\text{MTTF}_B}$$
  
al2 :=  $\frac{1}{\text{MTTR}_A}$  al3 :=  $\frac{1}{\text{MTTR}_B}$   
al1 :=  $\frac{1}{\text{MTTF}_A} \cdot \text{COV}_A$   
al2 :=  $\frac{1}{\text{MTTF}_B} + \frac{1}{\text{MTTR}_A}$  al2 := 0  
al1 :=  $\frac{1}{\text{MTTF}_B} \cdot \text{COV}_B$   
al2 := 0 al2 :=  $\frac{1}{\text{MTTF}_A} + \frac{1}{\text{MTTR}_B}$ 

The matrix equations are:

$$M := \begin{bmatrix} -a11 & a12 & a13 \\ a21 & -a22 & a23 \\ a31 & a32 & -a33 \end{bmatrix} V := \begin{bmatrix} -1 \\ 0 \\ 0 \end{bmatrix}$$
$$\begin{bmatrix} T1 \\ T2 \\ T3 \end{bmatrix} := M^{-1} \cdot V \qquad \begin{bmatrix} T1 \\ T2 \\ T3 \end{bmatrix} = \begin{bmatrix} 13536.52 \\ 12.834 \\ 26.776 \end{bmatrix}$$
$$MTTF := T1 + T2 + T3 \qquad \text{Sum of the Up states}$$
$$MTTF = 13576$$

### EXAMPLE 6 – NON-IDENTICAL, REPAIRABLE, COVERAGE < 1 AVAILABILITY MODEL, MARKOV ANALYSIS



Define Constants and Variables:

----

ľ

MTTF for unit A
MTTF for unit B
MTTR for covered unit A
failures
MTTR for uncovered unit A
failures
MTTR for covered unit B
failures
MTTR for uncovered unit B
failures
Coverage for unit A
Coverage for unit B

The Markov Availability solution for non-identical 1 or 2 units with coverage < 1 is computed as follows:

1990 PROCEEDINGS Annual RELIABILITY AND MAINTAINABILITY Symposium

The Coefficients of the Matrix:

al1 := 
$$\frac{1}{MTTF_A} + \frac{1}{MTTF_B}$$
  
al2 :=  $\frac{1}{MTTR_COV_A}$   
al3 :=  $\frac{1}{MTTR_COV_B}$  al4 := 0  
al4 := 0  
al1 :=  $\frac{1}{MTTF_A} \cdot COV_A$   
al2 :=  $\frac{1}{MTTF_B} + \frac{1}{MTTR_COV_A}$   
al2 := 0  
al1 :=  $\frac{1}{MTTF_B} \cdot COV_B$  al2 := 0  
al3 :=  $\frac{1}{MTTF_A} + \frac{1}{MTTR_COV_B}$   
al5 :=  $\frac{\frac{1-COV_A}{MTTF_A} + MTTR_UCOV_A + \frac{1-COV_B}{MTTF_B} \cdot MTTR_UCOV_B}{\frac{1-COV_B}{MTTF_A} + \frac{1-COV_B}{MTTF_B}}$   
al6 := 0  
al2 :=  $\frac{1}{MTTR_COV_A}$  al2 := 0  
al2 :=  $\frac{1}{MTTR_COV_A}$  al2 := 0  
al3 :=  $\frac{1}{MTTR_COV_A}$  al2 := 0  
al4 :=  $\frac{1}{MTTR_COV_A}$  al1 := 0  
al4 :=  $\frac{1}{MTTF_B}$  al3 := 0  
al4 :=  $\frac{1}{MTTF_B}$  al3 := 0  
al4 :=  $\frac{1}{MTTF_COV_A} + \frac{1}{MTTR_COV_B}$   
al5 := 0  
al4 :=  $\frac{1}{MTTF_A} + \frac{1-COV_B}{MTTF_B}$   
al5 := 0  
al4 :=  $\frac{1}{MTTF_A} + \frac{1-COV_B}{MTTF_B}$   
al5 := 0  
al4 :=  $\frac{1}{MTTF_A} + \frac{1-COV_B}{MTTF_B}$   
al5 := 0  
al5 :=  $\frac{1-COV_A}{A} + \frac{1-COV_B}{MTTF_B}$   
al5 := 0  
al6 := 0  
al5 :=  $\frac{1-COV_A}{A} + \frac{1-COV_B}{MTTF_A}$   
al5 := 0  
al5 :=  $\frac{1}{ATTF_A} + \frac{1-COV_B}{A}$   
al5 := 0  
al5 :=  $\frac{1}{ATTF_A} + \frac{1-COV_B}{A}$   
al5 := 0  
al5 :=  $\frac{1}{ATTF_A} + \frac{1-COV_B}{A}$   
al5 := 0  
al6 := 0  
al5 :=  $\frac{1}{ATTF_A} + \frac{1-COV_B}{A}$   
al5 := 0  
al5 :=  $\frac{1}{ATTF_A} + \frac{1}{ATTF_A}$ 

469

The matrix equations are:



Availability := A1 + A2 + A3 Sum of the Up states Availability = 0.99986

#### CONCLUSIONS

The MathCAD program has proven to be very useful in reliability analysis of simple to more complex fault tolerant systems. Sensitivity and trade-off analyses can be performed easily and within the program, and the results can be shown in graphical format for effective evaluation.

Libraries of function/macros can be developed that may be used to model every system configuration.

Text, formulas and graphics inside the MathCAD program, describing the entire analysis, can be used to generate formal documentation such as a reliability analysis report. The results are readable and easily understandable. There are no hidden functions/formulas or procedures in the body of the analysis. What you see is what you get.

Error messages are especially useful in the sequential analysis process, since every error is flagged on the spot when it first occurs and is shown throughout the analysis wherever it appears and affects other computations. This assures step-by-step error checking and optimum accuracy of the analysis.

The MathCAD tool helps the reliability engineer concentrate on modeling systems without getting involved in detailed mathematical computation of the system models.

#### REFERENCES

1. Godin, Edward E., "What you always wanted to know about reliability but were afraid to ask", Internal Unisys Document, December 1988.

2. Mathsoft, Inc. "MathCAD User's Guide", 1987.

#### BIOGRAPHY

Jahangir Ghajar Dowlatshahi Unisys Corporation, Computer Systems Division (CSD), Unisys Park, 3333 Pilot Knob Road, Eagan, MN 55121

Jahangir Dowlatshahi is a Principal Electrical Engineer at the System Effectiveness Group, Computer Systems Division, Unisys, Minnesota. His duties, among others, include reliability modeling of complex fault tolerant systems. He received his B.Sc. in Electrical Engineering from Peshawar University, Pakistan, and M.Sc. in Nuclear Engineering from Imperial College of Science and Technology, London University, England. Currently he is pursuing a Master of Science degree in Software Design and Development at the College of St. Thomas, in St. Paul, Minnesota. Since 1979 he has been working in the area of Reliability and Maintainability Engineering.

## 470

Т

#### 1990 PROCEEDINGS Annual RELIABILITY AND MAINTAINABILITY Symposium